

THYRISTORS



Silicon thyristors in metal envelopes, intended for power control applications.

The series consists of reverse polarity types (anode to stud) identified by a suffix R: BTW45-400R to 1200R.

QUICK REFERENCE DATA

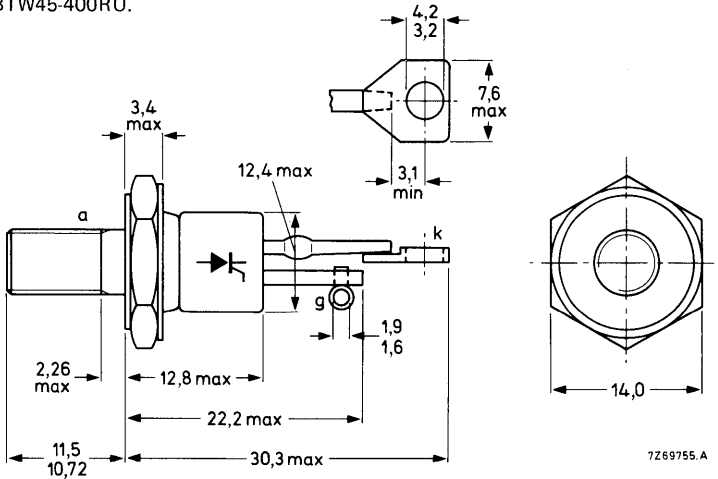
	BTW45-400R	600R	800R	1000R	1200R
Repetitive peak voltages $V_{DRM} = V_{RRM}$	max. 400	600	800	1000	1200 V
Average on-state current			$I_T(AV)$	max. 16 A	
R.M.S. on-state current			$I_T(RMS)$	max. 25 A	
Non-repetitive peak on-state current			$I_{TSM}$	max. 300 A	
Rate of rise of off-state voltage that will not trigger any device			$dV_D/dt$	< 200 V/ $\mu$ s	
On request (see ordering note on page 3)			$dV_D/dt$	< 1000 V/ $\mu$ s	

MECHANICAL DATA

Dimensions in mm

Fig. 1 TO-48: with metric M6 stud ( $\phi$  6 mm); e.g. BTW45-400R.

Types with  $\frac{1}{4}$  in x 28 UNF stud ( $\phi$  6,35 mm) are available on request. These are indicated by the suffix U: BTW45-400RU.



Net mass: 14 g  
 Diameter of clearance hole: max. 6,5 mm  
 Accessories supplied on request: 56264A  
 (mica washer, insulating ring, soldering tag)

Torque on nut: min. 1,7 Nm (17 kg cm)  
 max. 3,5 Nm (35 kg cm)

Supplied with the device:

1 nut, 1 lock washer

Nut dimensions across the flats;

M6: 10 mm

$\frac{1}{4}$  in x 28 UNF: 11,1 mm

## RATINGS

Limiting values in accordance with the Absolute Maximum System (IEC 134)

### Anode to cathode

		BTW45-400R	600R	800R	1000R	1200R
Non-repetitive peak voltages ( $t \leq 10$ ms)	$V_{DSM}/V_{RSM}$	max. 400	600	800	1000	1200 V
Repetitive peak voltages	$V_{DRM}/V_{RRM}$	max. 400	600	800	1000	1200 V
Crest working voltages	$V_{DWM}/V_{RWM}$	max. 300	400	600	700	800 V*
Average on-state current (averaged over any 20 ms period) up to $T_{mb} = 85$ °C			$I_T(AV)$		max.	16 A
R.M.S. on-state current			$I_T(RMS)$		max.	25 A
Repetitive peak on-state current			$I_{TRM}$		max.	200 A
Non-repetitive peak on-state current; $t = 10$ ms; half sine-wave; $T_j = 125$ °C prior to surge; with reapplied $V_{RWM}$ max			$I_{TSM}$		max.	300 A
$I^2 t$ for fusing ( $t = 10$ ms)			$I^2 t$		max.	450 A <sup>2</sup> s
Rate of rise of on-state current after triggering with $I_G = 400$ mA to $I_T = 60$ A; $dI_G/dt = 0,4$ A/ $\mu$ s			$dI_T/dt$		max.	100 A/ $\mu$ s

### Gate to cathode

Reverse peak voltage		$V_{RGM}$	max.	10 V
Average power dissipation (averaged over any 20 ms period)		$P_G(AV)$	max.	1 W
Peak power dissipation		$P_{GM}$	max.	5 W

### Temperatures

Storage temperature	$T_{stg}$	-55 to + 125 °C
Junction temperature	$T_j$	max. 125 °C

### THERMAL RESISTANCE

From junction to mounting base	$R_{th j-mb}$	=	1,33 °C/W
From mounting base to heatsink; with heatsink compound	$R_{th mb-h}$	=	0,2 °C/W
Transient thermal impedance ( $t = 1$ ms)	$Z_{th j-mb}$	=	0,1 °C/W

### OPERATING NOTE

The terminals should neither be bent nor twisted; they should be soldered into the circuit so that there is no strain on them.

During soldering the heat conduction to the junction should be kept to a minimum.

\* To ensure thermal stability:  $R_{th j-a} < 6,5$  °C/W (d.c. blocking) or  $< 13$  °C/W (a.c.). For smaller heatsinks  $T_{j max}$  should be derated. For a.c. see Fig. 2.

**CHARACTERISTICS**

**Anode to cathode**

On-state voltage

$I_T = 50 \text{ A}; T_j = 25 \text{ }^\circ\text{C}$

$V_T < 2 \text{ V}^*$

Rate of rise of off-state voltage that will not trigger

any device; exponential method;  $V_D = 2/3 V_{DRM \text{ max}};$   
 $T_j = 125 \text{ }^\circ\text{C}$

$dV_D/dt < 200 \text{ V}/\mu\text{s}$

Reverse current

$V_R = V_{RWM \text{ max}}; T_j = 125 \text{ }^\circ\text{C}$

$I_R < 3 \text{ mA}$

Off-state current

$V_D = V_{DWM \text{ max}}; T_j = 125 \text{ }^\circ\text{C}$

$I_D < 3 \text{ mA}$

Latching current;  $T_j = 25 \text{ }^\circ\text{C}$

$I_L < 150 \text{ mA}$

Holding current;  $T_j = 25 \text{ }^\circ\text{C}$

$I_H < 75 \text{ mA}$

**Gate to cathode**

Voltage that will trigger all devices

$V_D = 6 \text{ V}; T_j = 25 \text{ }^\circ\text{C}$

$V_{GT} > 1,5 \text{ V}$

Voltage that will not trigger any device

$V_D = V_{DRM \text{ max}}; T_j = 125 \text{ }^\circ\text{C}$

$V_{GD} < 200 \text{ mV}$

Current that will trigger all devices

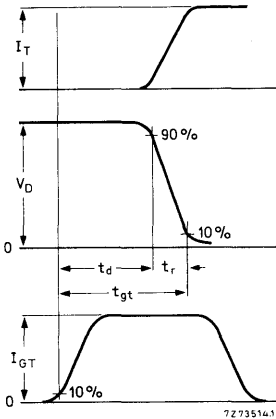
$V_D = 6 \text{ V}; T_j = 25 \text{ }^\circ\text{C}$

$I_{GT} > 75 \text{ mA}$

**Switching characteristics**

Gate-controlled turn-on time ( $t_{gt} = t_d + t_r$ ) when  
 switched from  $V_D = V_{DWM \text{ max}}$  to  $I_T = 100 \text{ A};$   
 $I_{GT} = 400 \text{ mA}; dI_G/dt = 1 \text{ A}/\mu\text{s}; T_j = 25 \text{ }^\circ\text{C}$

$t_{gt} < 1 \mu\text{s}$   
 $t_r < 0,5 \mu\text{s}$



Gate-controlled turn-on time definition.

**ORDERING NOTE**

Types with  $dV_D/dt$  of  $1000 \text{ V}/\mu\text{s}$  are available on request. Add suffix C to the type number when ordering; e.g. BTW45-400RC.

\*Measured under pulse conditions to avoid excessive dissipation.

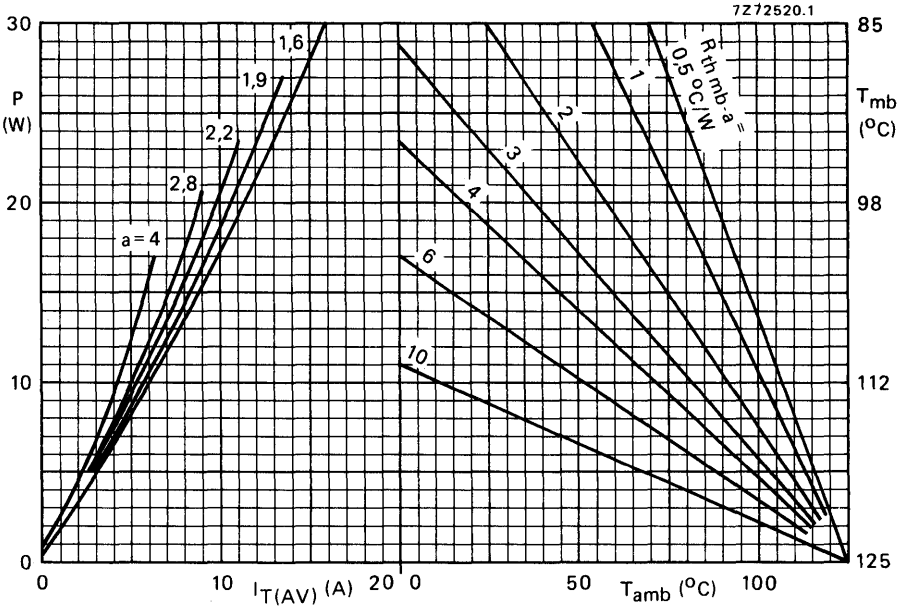


Fig. 2.

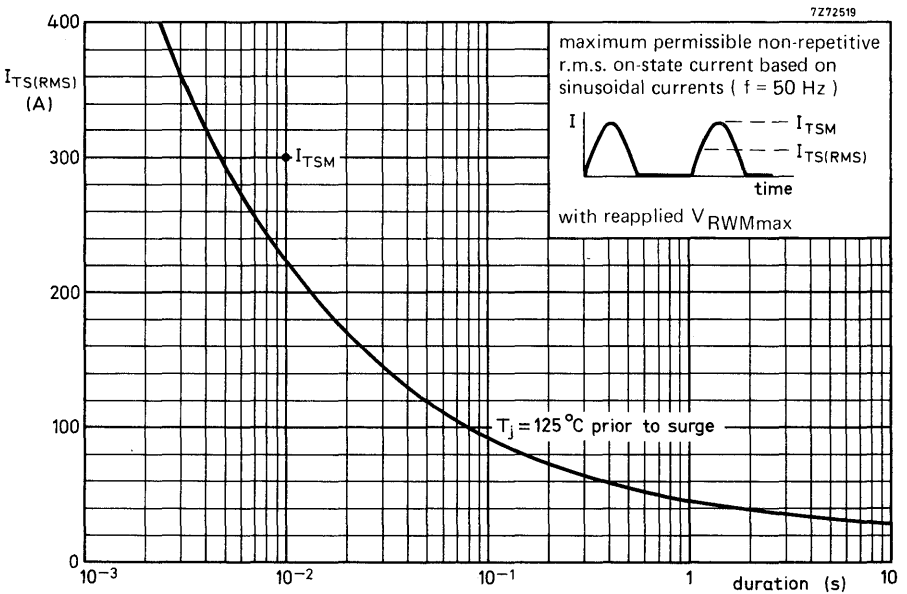


Fig. 3.

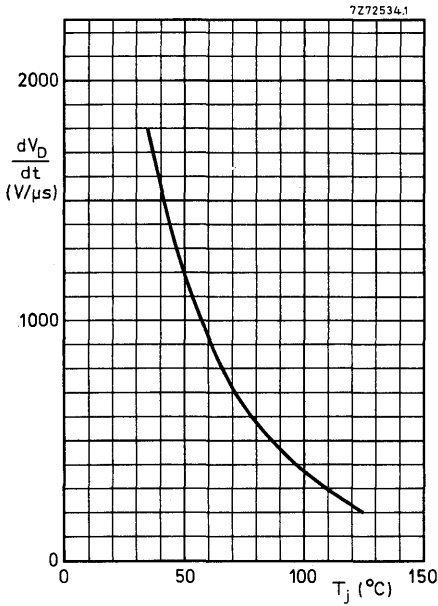


Fig. 4 Maximum rate of rise of off-state voltage that will not trigger any device (exponential method) as a function of  $T_j$ .

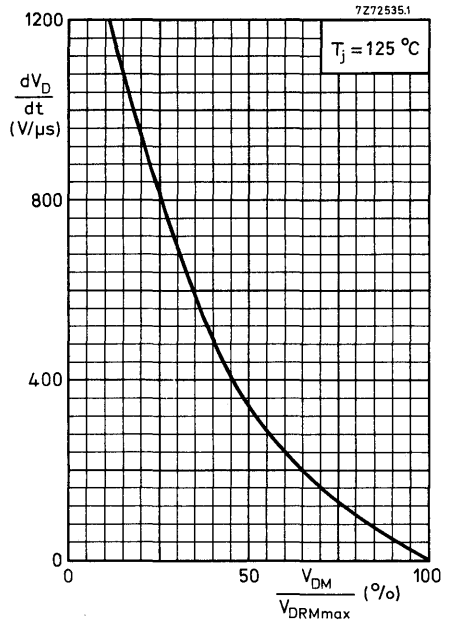


Fig. 5 Maximum rate of rise of off-state voltage that will not trigger any device (exponential method) as a function of applied voltage.

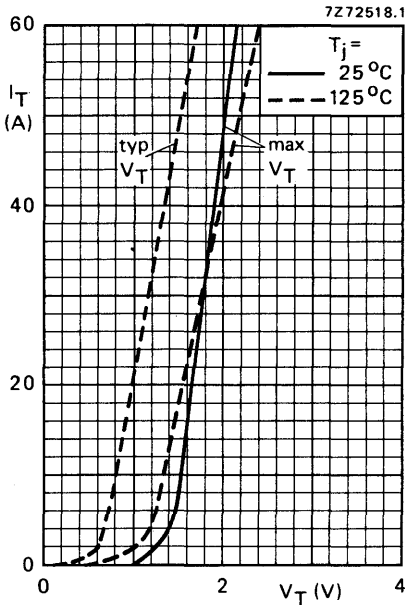


Fig. 6.

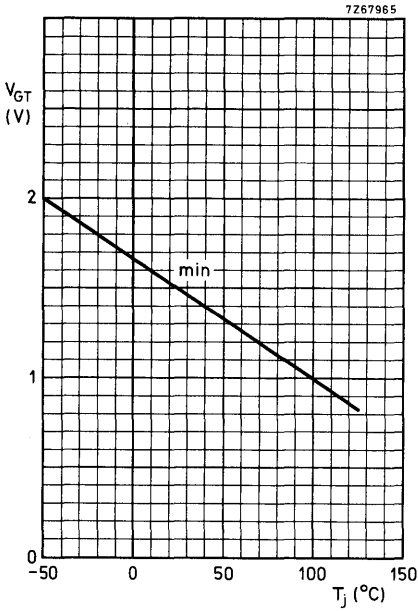


Fig. 7 Minimum gate voltage that will trigger all devices as a function of  $T_j$ .

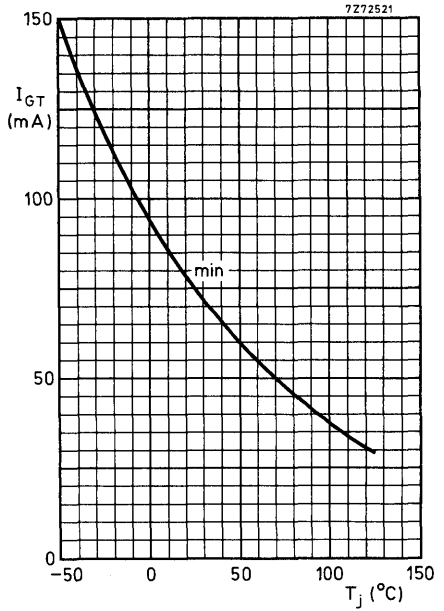


Fig. 8 Minimum gate current that will trigger all devices as a function of  $T_j$ .

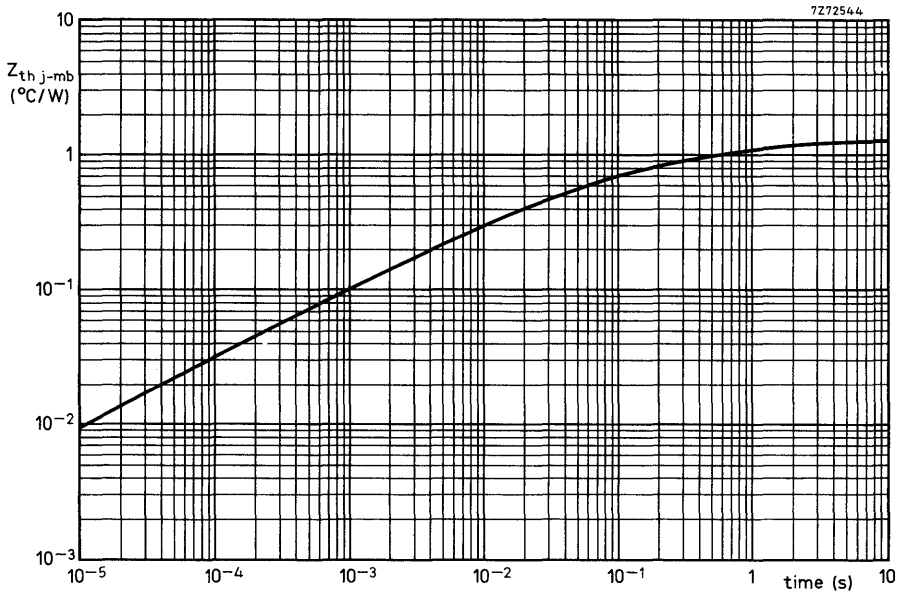


Fig. 9.